

HALOGEN

FREE

## STP13N95K3-VB Datasheet

# N-Channel 900V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	900				
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V 0.60				
Q <sub>g</sub> max. (nC)	73				
Q <sub>gs</sub> (nC)	9				
Q <sub>gd</sub> (nC)	17				
Configuration	Single				

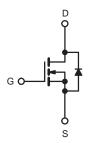
TO-220AB

#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>a</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting



N-Channel MOSFET

G D S Top View

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	900	1/	
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	9		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		8	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28		
Linear Derating Factor				1.4	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	226	mJ	
Maximum Power Dissipation			P <sub>D</sub>	156	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope T <sub>J</sub> = 125 °C		dV/dt	37	V/ns		
Reverse Diode dV/dt <sup>d</sup>			28			
Soldering Recommendations (Peak Temperature) c for 10 s				300	°C	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 4 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \leq I_{D}, \, dI/dt = 100$  A/µs, starting  $T_{J} = 25$  °C.

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THERMAL RESISTANCE RATINGS						
PARAMETER SYMBOL TYP. MAX. UNIT						
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		•					•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		900	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.78	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2	-	4	٧
	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage			$V_{GS} = \pm 30 \text{ V}$		-	± 1	μΑ
		V <sub>DS</sub> =	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		-	1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 6 A	-	0.60	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub>	s = 30 V, I <sub>D</sub> = 6 A	-	3.5	-	S
Dynamic						·	
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	1227	-	
Output Capacitance	C <sub>oss</sub>	1	$V_{DS} = 0 V$ , $V_{DS} = 100 V$ ,	-	65	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		-	4	-	pF
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V 0V 500V V 0V		-	50	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>	$V_{DS} = 0.0$	$V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$		160	-	
Total Gate Charge	Qg			-	35	73	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 6 \text{ A}, V_{DS} = 520 \text{ V}$		-	9	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	17	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 6 A,		-	16	32	
Rise Time	t <sub>r</sub>			-	19	38	]
Turn-Off Delay Time	t <sub>d(off)</sub>		$V_{GS} = 320 \text{ V}, \text{ Hz} = 0 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ Rg} = 9.1 \Omega$		35	70	ns
Fall Time	t <sub>f</sub>			-	18	36	
Gate Input Resistance	$R_{g}$	f = 1 MHz, open drain		-	0.81	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	28	A .
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 6 A, V <sub>GS</sub> = 0 V		-	1.0	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, $I_F = I_S = 6 \text{ A}$ , $I_R = 100 \text{ A/}\mu\text{s}$ , $I_R = 25 \text{ V}$		-	309	618	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	3.8	7.6	μC
Reverse Recovery Current	I <sub>RBM</sub>			_	21	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

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## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

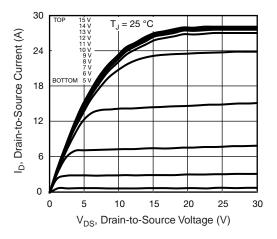


Fig. 1 - Typical Output Characteristics

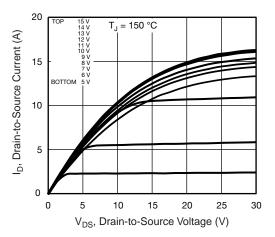


Fig. 2 - Typical Output Characteristics

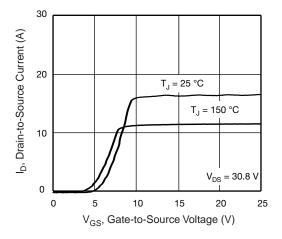


Fig. 3 - Typical Transfer Characteristics

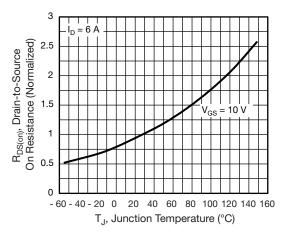


Fig. 4 - Normalized On-Resistance vs. Temperature

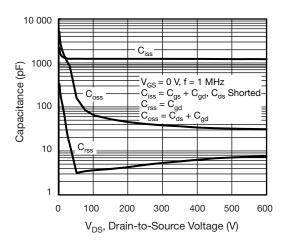


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

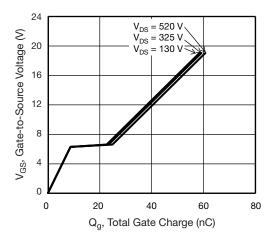


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



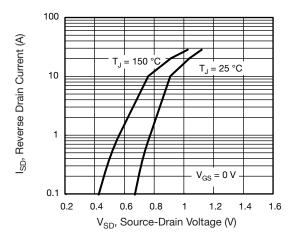


Fig. 7 - Typical Source-Drain Diode Forward Voltage

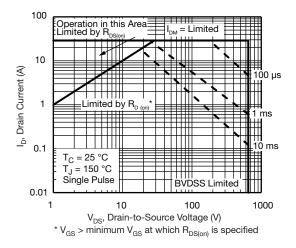


Fig. 8 - Maximum Safe Operating Area

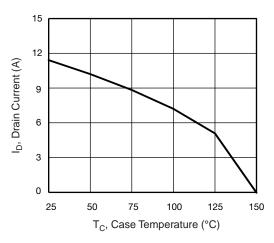


Fig. 9 - Maximum Drain Current vs. Case Temperature

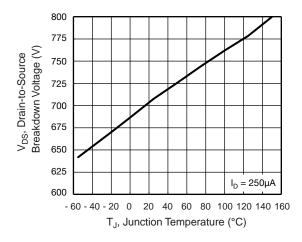


Fig. 10 - Temperature vs. Drain-to-Source Voltage

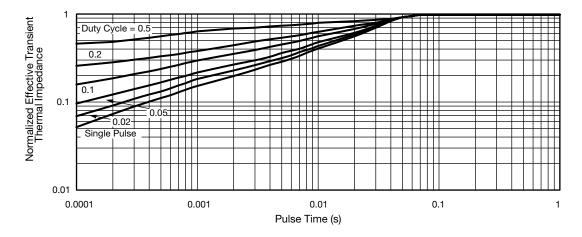


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



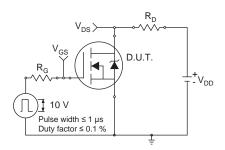


Fig. 12 - Switching Time Test Circuit

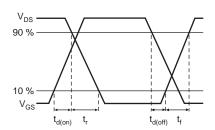


Fig. 13 - Switching Time Waveforms

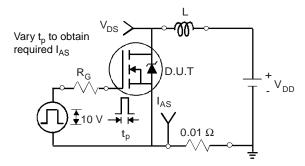


Fig. 14 - Unclamped Inductive Test Circuit

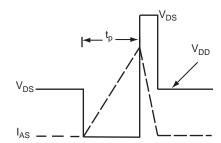


Fig. 15 - Unclamped Inductive Waveforms

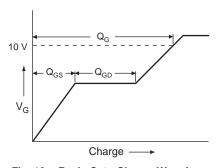


Fig. 16 - Basic Gate Charge Waveform

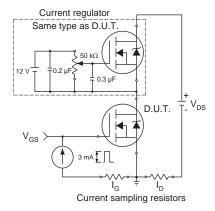
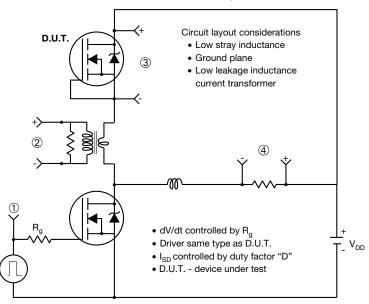


Fig. 17 - Gate Charge Test Circuit



## Peak Diode Recovery dV/dt Test Circuit



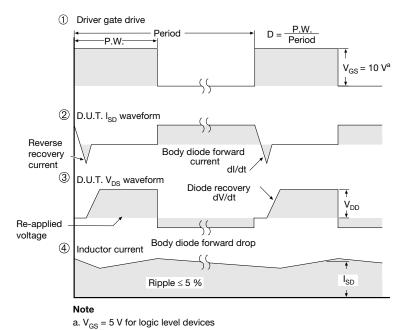
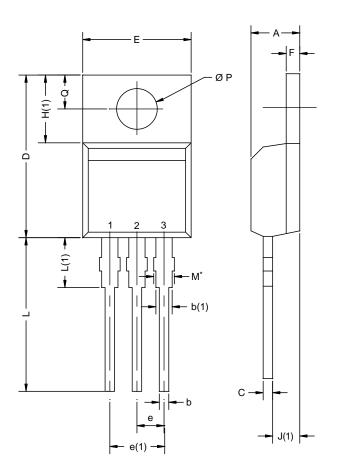


Fig. 18 - For N-Channel



# **TO-220AB**



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

### Notes

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 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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